

IEEE 802.3 IMAT Test Attendance

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| Name | Affiliation | Employer |
|----------------------|--|--|
| Aekins, Rob | Legrand | Legrand |
| Akbaba, Enis | Maxim Integrated Products | Maxim Integrated Products |
| Anslow, Peter | Independent | INDEPENDENT |
| Araki, Nobuyasu | Yazaki Corporation | Yazaki Corporation |
| Aronson, Joseph | Texas Instruments Incorporated | Texas Instruments Incorporated |
| Baldwin, Thananya | Keysight Technologies | Keysight Technologies |
| Banar, Jafar | Chalmers University of technology | |
| Beaudoin, Denis | Texas Instruments Inc. | Texas Instruments Incorporated |
| Bhatt, Vipul | II-VI Incorporated | Finisar Corporation |
| Bliss, Will | Broadcom Corporation | Broadcom Corporation |
| Boyer, Rich | Aptiv Signal and Power Solutions | Aptiv - Signal and Power Solutions |
| Brooks, Paul | VIAVI solutions | Viavi solutions GmbH |
| Bruckman, Leon | HUAWEI | HUAWEI |
| Calvin, John | Keysight Technologies | Keysight Technologies |
| Carlson, Steven | HSD;Bosch;Ethernovia | High-Speed Design Inc. |
| Carty, Clark | Cisco Systems, Inc. | Cisco Systems, Inc. |
| Dawson, Fred | Chemours Canada Company | Chemours Canada Company |
| Deandrea, John | Finisar Corporation | Finisar Corporation |
| DiBiaso, Eric | TE Connectivity | TE Connectivity |
| Dube, Kathryn | UNH-IOL | UNH-IOL |
| Effenberger, Frank | Huawei Technologies Co., Ltd | Futurewei Technologies |
| Eitel, Cornelia | Hirschmann Automation and Control GmbH | Hirschmann Automation and Control, Inc. |
| Ewen, John | Marvell | Marvell |
| Feyh, German | Broadcom Corporation | Broadcom Corporation |
| Fritsche, Matthias | HARTING Technologie Gruppe | HARTING Technologie Gruppe |
| Frosch, Richard | Phihong USA Inc, | Phihong USA Inc, |
| Fukuoka, Takashi | AutoNetworks Technologies Ltd.; Sumitomo Electric Industries, Ltd. | Sumitomo Electric Industries, LTD |
| Geng, Limin | HUAWEI | HUAWEI |
| gianordoli, stefan | GG-group | |
| Gorshe, Steven Scott | Microchip Technology, Inc. | Microchip Technology, Inc. |
| Goto, Hideki | Toyota Motor Corporation | Toyota Motor Corporation |
| Graber, Steffen | Pepperl+Fuchs SE | Pepperl+Fuchs SE |
| Grow, Robert | RMG Consulting, KDPOF | RMG Consulting |
| Haser, Alexandra | Molex Incorporated | Molex Incorporated |
| Heck, Howard | Intel Corporation | Intel Corporation |
| Huber, Thomas | Nokia | Nokia |
| HYAKUTAKE, YASUHIRO | Adamant Namiki Precision Jewel Co., Ltd. | Adamant Namiki Precision Jewel Co., Ltd. |
| Intrater, Gideon | Dialog Semiconductor | Dialog Semiconductor |
| Islinger, Tobias | Infineon Technologies AG | Infineon Technologies AG |
| Jiang, Tong | Huawei Technologies Co. Ltd | Huawei Technologies Co. Ltd |
| Johnson, John | Broadcom Corporation | Broadcom Corporation |
| Kabra, Lokesh | Synopsys, Inc. | Synopsys, Inc. |
| Kadry, Haysam | Ford Motor Company | Ford Motor Company |
| Kao, Chienping | Cornelis Networks | Intel Corporation |
| Kim, Kihong/Joshua | Hirose Electric (USA), Inc. | Hirose Electric (USA), Inc. |
| Kim, Yongbum | Tenstorrent | Tenstorrent |
| Kimber, Eric | Semtech Ltd | Semtech Ltd |
| Kobayashi, Shigeru | AIO Core | AIO Core |
| Kocsis, Sam | Amphenol Corporation | Amphenol Corporation |
| Kondo, Taiji | MegaChips Corporation | MegaChips Corporation |
| Kota, Kishore | Inphi Corporation | |
| Lackner, Hans | QoSCom GmbH | QoSCom GmbH |
| Latchman, Ryan | MACOM | MACOM |

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| Name | Affiliation | Employer |
|-------------------------------|--|--|
| Laubach, Mark | IEEE Member / Self Employed | IEEE member / Self Employed |
| Law, David | Hewlett Packard Enterprise | Hewlett Packard Enterprise |
| Lee, Han Hyub | | ETRI |
| Lewis, David | Lumentum | Lumentum Inc. |
| Lewis, Jon | Dell Technologies | Dell Technologies |
| Lingle, Robert | OFS | OFS |
| Liu, Hai-Feng | HG Genuine | HG Genuine |
| Lusted, Kent | Intel Corporation | Intel Corporation |
| Maguire, Valerie | The Siemon Company | The Siemon Company |
| Mak, Gary | inphi | Inphi Corporation |
| Maniloff, Eric | Ciena Corporation | Ciena Corporation |
| Marris, Arthur | Cadence Design Systems, Inc. | Cadence Design Systems, Inc. |
| MASUDA, TAKEO | OITDA | OITDA |
| McCarthy, Mick | Analog Devices Inc. | Analog Devices Inc. |
| McMillan, Larry | Western Digital Corporation | Western Digital Corporation |
| Milicevic, Mario | Maxlinear Corp | MaxLinear |
| mortazavi, sanaz | Volkswagen Ag | Volkswagen Ag |
| Nariya, Makoto | Sony Semiconductor Solutions Corporation | Sony Semiconductor Solutions Corporation |
| Nering, Raymond | Cisco Systems, Inc. | Cisco Systems, Inc. |
| Neulinger, Christian | MD Elektronik | MD Elektronik |
| New, Anthony | Prysmian Cables & Systems | Prysmian Cables & Systems |
| Nicholl, Gary | Cisco Systems, Inc. | Cisco Systems, Inc. |
| Nicholl, Shawn | Xilinx | Xilinx |
| Nikolich, Paul | Self Employed | Paul Nikolich |
| Ofelt, David | Juniper Networks, Inc. | Juniper Networks, Inc. |
| Pardo, Carlos | Knowledge Development for POF SL | Knowledge Development for POF SL |
| Parsons, Earl | CommScope, Inc. | CommScope, Inc. |
| Pepper, Gerald | Keysight Technologies | Keysight Technologies |
| Perez De Aranda Alonso, Ruben | KDPOF | Knowledge Development for POF SL |
| Petrarca, Ryan | TDK Corporation | TDK Corporation |
| Pittala, Fabio | Huawei Technologies Duesseldorf GmbH | Huawei Technologies Duesseldorf GmbH |
| Potterf, Jason | Cisco Systems, Inc. | Cisco Systems, Inc. |
| Powell, William | INDEPENDENT | INDEPENDENT |
| Proell, Dieter | Siemens AG | Siemens AG |
| Ren, Hao | HUAWEI | Huawei Technologies Co., Ltd |
| Renteria, Victor | Bel Fuse | Bel Fuse |
| Sambasivan, Sam | AT&T | AT&T |
| Savi, Olindo | Hubbell Incorporated | Hubbell Incorporated |
| Schmitt, Matthew | Cable Television Laboratories Inc. (CableLabs) | Cable Television Laboratories Inc. (CableLabs) |
| Schweitz, Laura | Turck Inc. | Turck Inc. |
| She, Qingya | Fujitsu Network Communications | Fujitsu Network Communications |
| Shoval, Ayal | Synopsys, Inc. | Synopsys, Inc. |
| Slavick, Jeff | Broadcom Corporation | Broadcom Inc |
| Sommers, Scott | Molex Incorporated | Molex LLC |
| Stewart, Heath | Analog Devices, Inc. | Analog Devices Inc. |
| Stover, David | Analog Devices | Analog Devices Inc. |
| Sun, Yi | OFS | |
| Takahashi, Satoshi | POF Promotion | Self Employed |
| TAZEBAY, MEHMET | Broadcom Corporation | Broadcom Corporation |
| Theodoras, James | HG Genuine | HG Genuine |
| Tracy, Nathan | TE Connectivity | TE Connectivity |
| Tsuzaki, Nozomi | Independent | |
| Tu, Mike | Broadcom Corporation | Broadcom Corporation |
| Ulrichs, Ed | Intel Corporation | Intel |

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| Name | Affiliation | Employer |
|----------------------|--|------------------------------|
| Umnov, Alexander | Independent | Infinera Corporation |
| Voss, Robert | Panduit Corp. | Panduit Corp. |
| Wang, Roy | Hewlett Packard Enterprise | Hewlett Packard Enterprise |
| Wang, Ruoxu | Huawei Technologies Co., Ltd | Huawei Technologies Co., Ltd |
| Weaver, James | Arista Networks | Arista Networks |
| Weber, Karl | Beckhoff Automation | Beckhoff Automation |
| Wienckowski, Natalie | General Motors Company | General Motors Company |
| Wu, Mau-Lin | MediaTek Inc. | MediaTek Inc. |
| Xu, Dayin | Rockwell Automation | Rockwell Automation |
| Yamada, Osamu | Yazaki Corporation | |
| Yi, Louise | Foxconn Electronics Inc. | Foxconn Electronics Inc. |
| Zhiwei, Yang | ZTE Corporation | ZTE Corporation |
| Zimmerman, George | CME Consulting/ADI, APL Group, Cisco Systems, CommScope, Marvell, SenTekse LLC | CME Consulting |